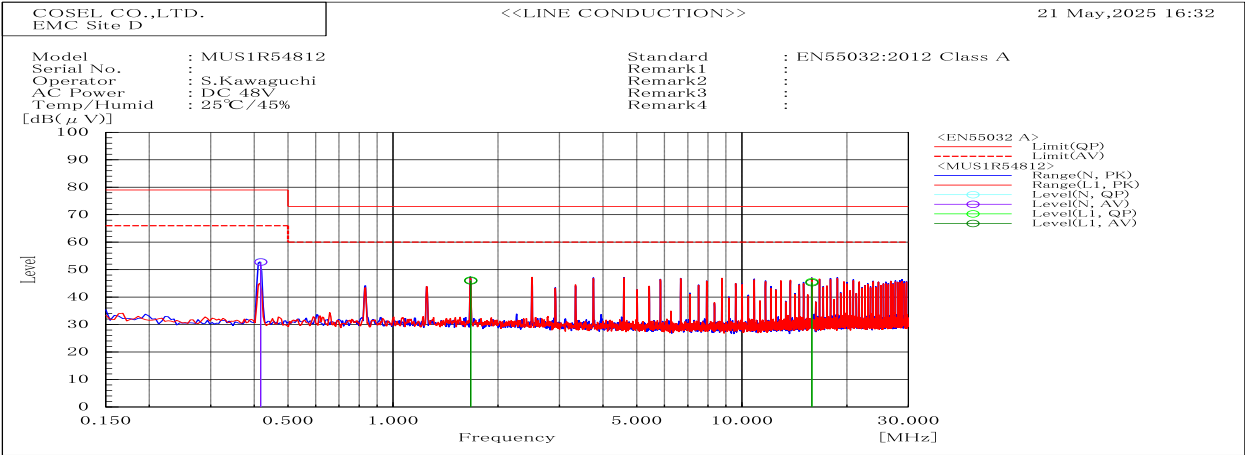
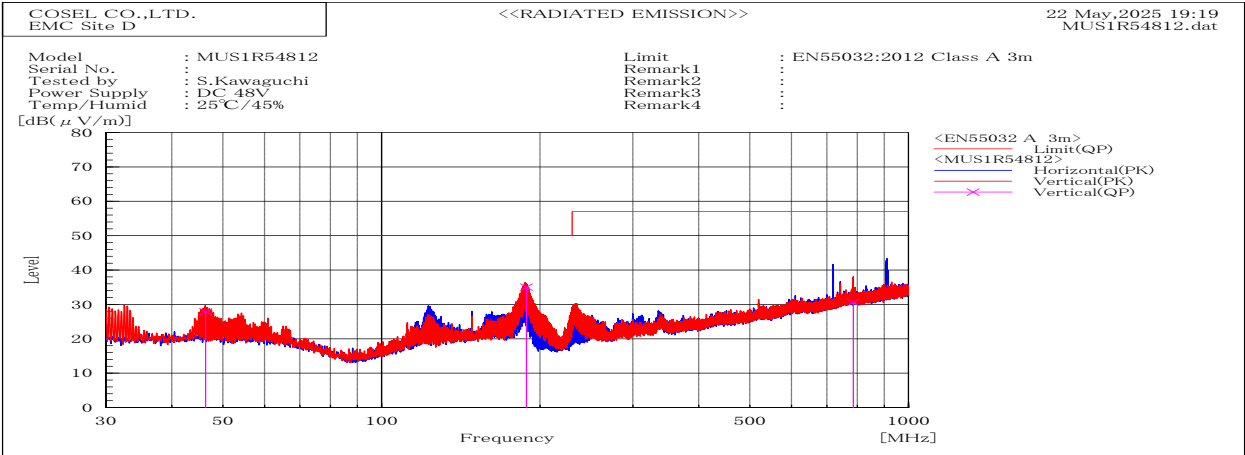


DATA SHEET		Date	22-May-25
Model	MUS1R54812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



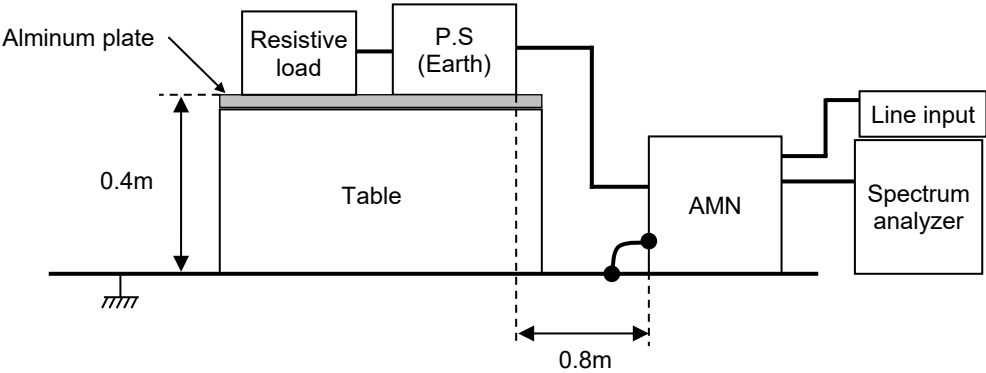
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.67	L1	46.2	45.9	73	60	26.8	14.1	Pass	
15.87	L1	45.6	45.3	73	60	27.4	14.7	Pass	
0.417	N	52.9	52.8	79	66	26.1	13.2	Pass	



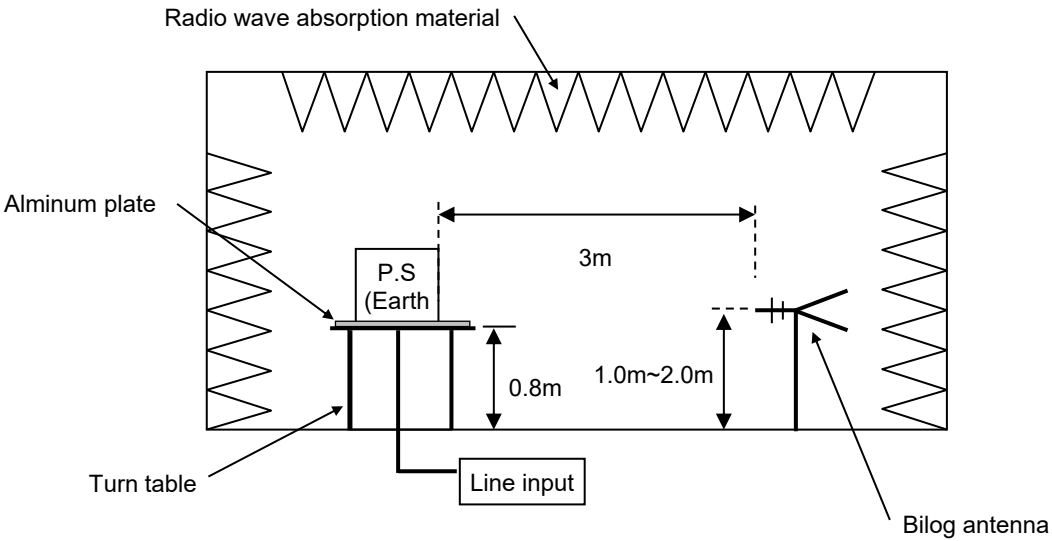
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
188.365	V	Stable	35	50	15	Pass	100.2	33.2		
785.591	V	Stable	30.6	57	26.4	Pass	150.6	0		
46.379	V	Stable	27.8	50	22.2	Pass	100	24.4		

DATA SHEET		Date	22-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

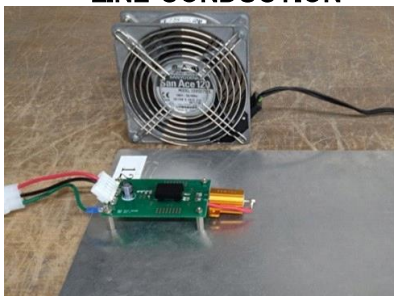


Conditions

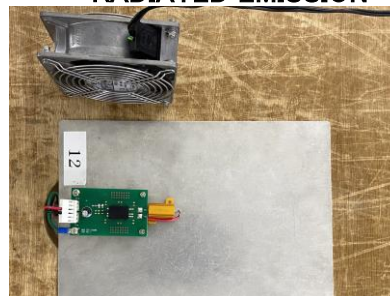
Test : EMI
Model Name: MUS1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

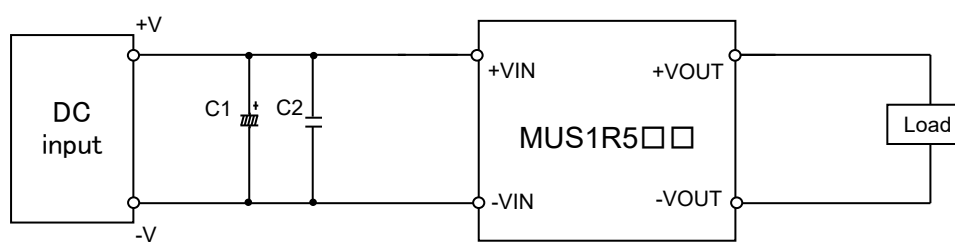


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

- | | | | |
|------|-----------|-----------------|---|
| C1 : | MUS1R505□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R512□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R524□ | - | |
| C2 : | MUS1R505□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUS1R512□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUS1R524□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

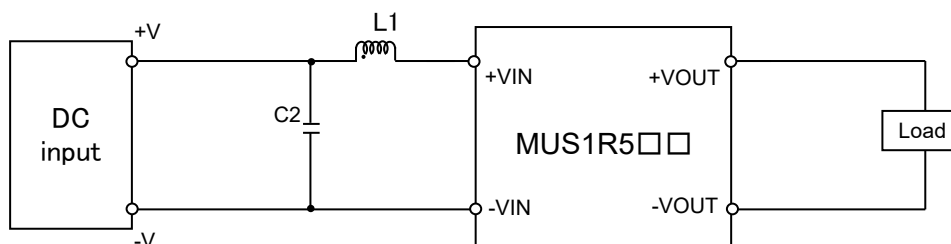


Fig.2 MUS1R548□ Testing circuitry

- | | | | |
|------|-----------|------------------|--|
| C2 : | MUS1R548□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUS1R548□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |